


<b>Search Notes</b> 	<b>Application/Control No.</b> 10540997	<b>Applicant(s)/Patent Under Reexamination</b> LEE, CHEOL-SU
	<b>Examiner</b> DEBRA ANTONIENKO	<b>Art Unit</b> 3689

SEARCHED			
Class	Subclass	Date	Examiner
705	1	08/17/2008	DA

SEARCH NOTES		
Search Notes	Date	Examiner
East - see search notes	08/17/2008	DA

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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